Searcn Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/788,660	LEE ET AL.	
Examiner	Art Unit	
Jezia Rilev	1637	

SEARCHED				
Class	Subclass	Date	Examiner	
536	4.1 26.6	5/23/2007	JR	

INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
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REVIEW PARENTS CASES	5/23/2007	JR